

产品规格书

SPECIFICATIONS FOR PRODUCT

产品类型 TYPE : SMD3225

产品规格 SPEC : 32.768MHz/3225/10PF/10PPM AEC-Q200

产品型号 P/N : AD-CJ13-327681010C30

日期 DATE : 2022/04/02

核准及签名			おりて
R&D APPR. SIGNATURED			DEPT.
拟制	审核	批准	频率器件事业部
ISSUE	CHECK	APPROVAL	
Ivan 2022/04/02	Abbey 2022/04/02	Ken 2022/04/02	

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JIANGSU CHANGJING ELECTRONICS TECHNOLOGY CO., LTD.

SMCE3225 4 pads Crystal Resonator

AD-CJ13-327681010C30

1. Scope:

- 1.1 This specification applies to the RoHS/SONY compliance quartz crystal unit with a frequency of 32.768MHz which will be used in crystal oscillator applications.
- 1.2 AEC-Q200 qualified

2. Construction:

2.1 Type of Quartz Resonator: SMCE3225 4pads

3. Electrical Characteristics

3.1 Nominal Frequency(f): 32.768MHz

3.2 Load Capacitance(C_L): 10pF

3.3 Frequency Tolerance(△f/f): ±10ppm

3.4 Frequency Temperature Stability: ±30ppm(Ref.@25℃)

3.5 Resonance Resistance(ohm): 40ohms Max

3.6 Osc mode: Fundamental mode

3.7 Shunt Capacitance(C_0): <2pF

3.8 Drive Level(D_L): <100 μ W

3.9 Operating Temperature Range(T_{OPR}): -40 to + 105

3.10 Storage Temperature Range(T_{STG}): -55 to + 125°C

3.11 Insulation Resistance(IR): >500 M ohms

3.12 Aging($\triangle f_A$): ±3ppm per Year

1

4. Reliability Specifications

This is the quality control and quality assurance and reliability tests performance data for the RoHS/

AEC-Q200 compliance 32.768MHz SMCE3225 4pads crystal resonators

related to the specification and approval sheet provided by JSCJ.

Standard test condition (TEMP.: 20±5°C. Relative humidity: 65±20%)

For any discrepancy in GO/NG, test will be done at TEMP.25±2°C, R.H. 65±5%.

NO.	PROCESS	SPECIFICATION	TEST METHOD
4.1	Temperature Cycle	Frequency change after test ≤± 5ppm.Resonance resistance change after test ≤5ohms.	taken after DUT being left at room temperature for 24±2 hours.
4.2	High Temperature Storage	Frequency change after test ≤± 5ppm.Resonance resistance change after test ≤5ohms.	Spending 1000 hrs at 85°C±3°C constant temperature. Measurement taken after DUT being left at room temperature for 24±2 hours.
4.3	Biased Humidity	Frequency change after test ≤± 5ppm.Resonance resistance change after test ≤5ohms.	Spending 1000 hrs at 85 °C \pm 3 °C, with 85%R.H, Then keep the DUT in dry oven at 25 \pm 5 °C for 24 hour. Measurement taken after DUT being left at room temperature for 1 to 2 hours.
4.4	Operational Life	5ppm.Resonance resistance change after test ≤5ohms.	Spending 1000 hrs at 125°C±3°C constant temperature. Measurement taken after DUT being left at room temperature for 24±2 hours.
4.5	Vibration	Frequency change after test ≤± 5ppm.Resonance resistance change after test ≤5ohms.	Apply 1.52mm vibration at sweep frequency 10^{\sim} 2000Hz, 5g's for 20min 12 cycles in each direction of 3 axis. Measurement taken after 1 hour.
4.6	Mechanical Shock	Frequency change after test ≤± 5ppm.Resonance resistance change after test ≤5ohms.and exhibit no visible damage.	Peak 100gal, normal width 6ms half sine wave form, 3.7m/s, 3 cycles / direction. Measurement taken after 1 hour.
4.7	Solderability	Terminals shall be covered more then 95% with solder.	Passed through the re-flow oven under the following condition. Preheat 150 to 180°C for 60 to 120sec, and soldering time for 20s ± 5s at 235°C, peak soldering time for 5s ±0.5s betweein 240 and 250°C. There is no need to do functional test. 8-12X magnifier.
4.8	Terminal Strength	No visible damage	Mount on a glass-epoxy board (100x50x1.6mm), then bend to 2mm displacement (velocity 1mm/sec) and keep for 5 seconds. or pulling force 1.8kg for at least 60 seconds.
4.9	Resistance to Soldering Heat	Frequency change after test ≤± 5ppm.Resonance resistance change after test ≤5ohms.	Passed through the re-flow oven under the following condition. Preheat 150 to 180°C for 60 to 120sec, and sodering time for 60s max at 235°C, peak soldering time for 10s max at 265°C max. Measurement taken after DUT being left at room temperature for at least 2 hours.
4.40	OTUEDO		
4.10	OTHERS		

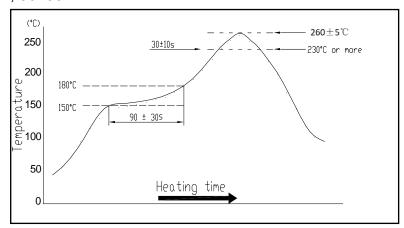
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Recommended Reflow soldering condition

5. Recommended Reflow soldering condition (SMD)

Solder profile

Peak: 260±5°C Soldering zone: 230°C or more, 30±10s. Pre-heating zone 1: 150 \sim 180°C, 90±30s



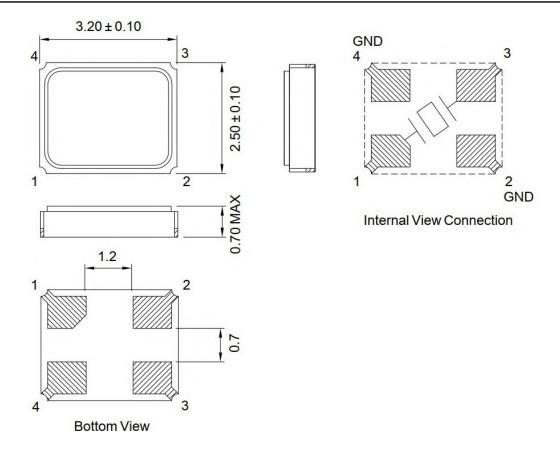
Temperature profile for reflow soldering

6. Soldering iron method

Bit temperature: 350±10°C Application time of soldering iron:3+1 s. For other procedures, refer to IEC 60068-2-20.

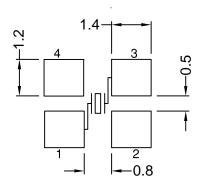
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Package Outline Dimensions



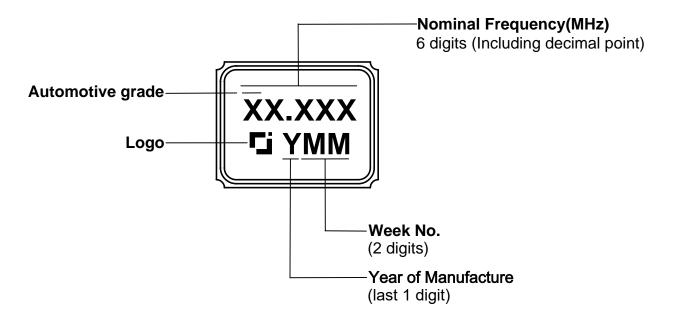
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Suggested Pad Layout

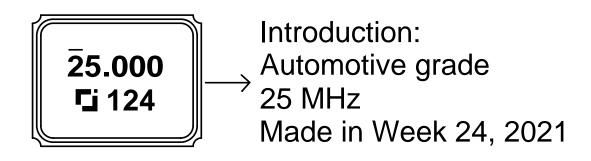


Marking

Procedure: Laser

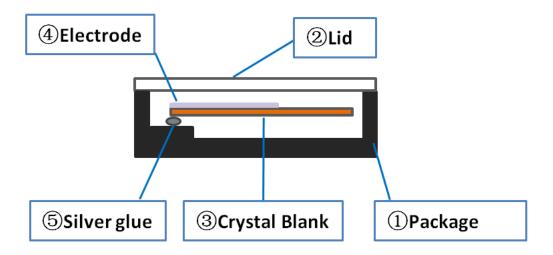


For example:

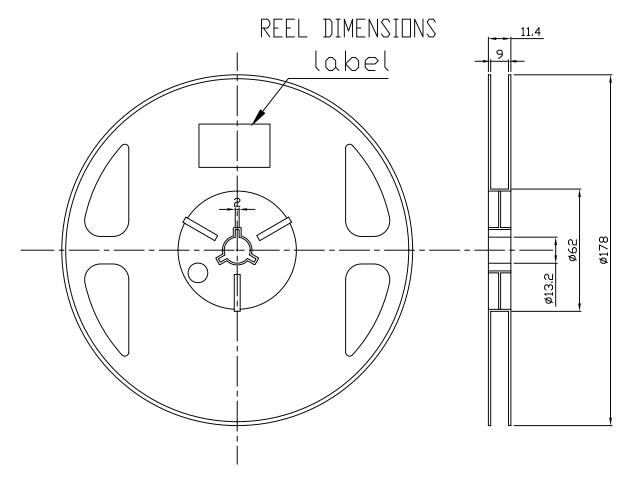


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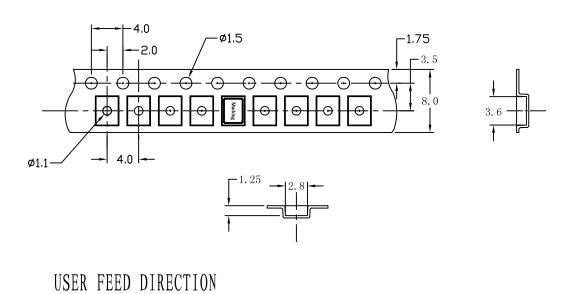
Inside Structure



No.	Components	Materials
1	Package	Ceramic(Al ₂ O ₃)
2	Lid	KV(Fe/Ni/Co)
3	Crystal blank	SiO ₂
4	Electrode	Ag、Cr
5	Silver glue	Ag、CH ₃ OH、SiO ₂

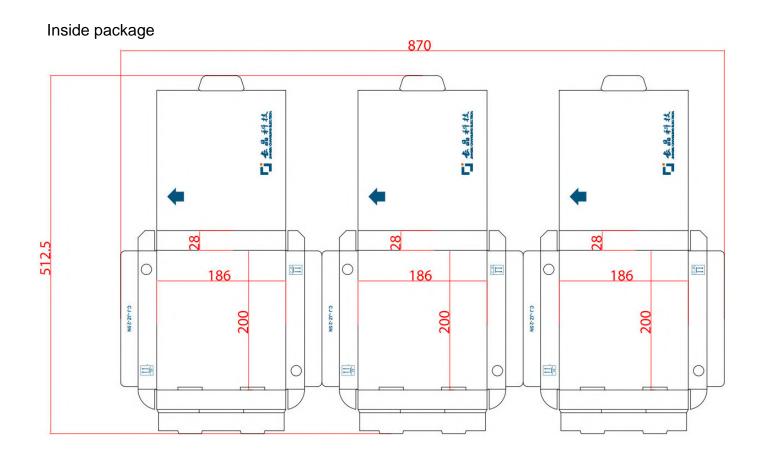


EMBOSSED TYPE DIMENSIONS

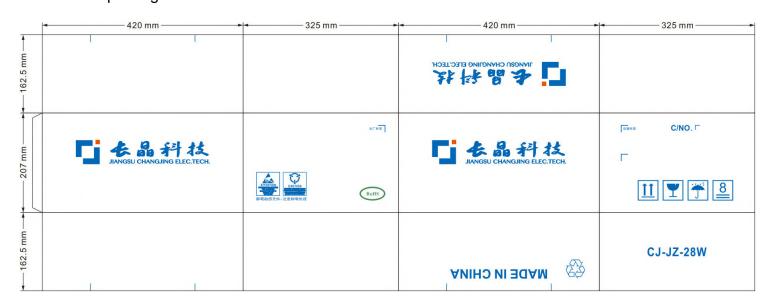


7

Package



Outside package



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